

# RELIABILITY MONITOR

PROCESS: 2P, 1M, 0.8um,ThinEP/Sil,ThinOx NdPdDSD,BPSG,N+ESD,CtEtch,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS87C520	A15-	FEB '02	28780	0206	ATP (Amkor, PI)	DK101111AA	PLCC	336	77	0
DS87C520	A15-	FEB '02	28780	0206	ATP (Amkor, PI)	DK101111AA	PLCC	1000	77	0

TOTALS:

FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

# RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	NOV '01	28558	0143	ATP (Amkor, PI)	DK122629AA	SOIC	336	80	0
DS1803	A2	APR '02	29506	0204	OSEP	DE113317AAB	SOIC	1000	80	0

TOTALS: FAIL RATE (Fits): 15 DEVICE HRS: 6.31E+07 0

# RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+M2,WJ BPSG,N+ESD,CtE,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80CH11	A4	DEC '01	28601	0113	ATK (Amkor, K)	DN036754AA	LQFP	336	80	0
DS80CH11	A4	DEC '01	28601	0113	ATK (Amkor, K)	DN036754AA	LQFP	1000	80	0

TOTALS: FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0

# RELIABILITY MONITOR

PROCESS: D6W-1P2M,HPVt,E2,TCZ PBL:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1100	A3	OCT '01	28535	0126	ATP (Amkor, PI)	DK114601AD	SOIC	336	77	0
DS1100	A3	JAN '02	28614	0132	ATP (Amkor, PI)	DK115002AK	SOIC	336	77	0
DS1100	A3	OCT '01	28535	0126	ATP (Amkor, PI)	DK114601AD	SOIC	1000	77	0
DS1100	A3	JAN '02	28614	0132	ATP (Amkor, PI)	DK115002AK	SOIC	1000	77	0

TOTALS:

FAIL RATE (Fits): 6 DEVICE HRS: 1.45E+08 0

# RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode, Ti/TiN M1+M2 , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	APR '02	29506	0204	OSEP	DE113317AAB	SOIC	500	80	0

TOTALS:

FAIL RATE (Fits): 24 DEVICE HRS: 3.77E+07 0

# RELIABILITY MONITOR

PROCESS: D6S-1P1M,HPVt,N+ESD,TCN3 ALOCOS:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2118M	C1	MAR '02	28819	0143	ATK (Amkor, K)	DN120700AB	SSOP	336	77	0
DS2118M	C1	MAR '02	28819	0143	ATK (Amkor, K)	DN120700AB	SSOP	1000	77	0

TOTALS:

FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

# RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, Pdepletion, Low Vts , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21Q43	A3-	SEP '01	27880	0047	Stats	DC036714AA	LQFP	336	70	0
DS21Q43	A3-	SEP '01	27880	0047	Stats	DC036714AA	LQFP	1000	70	0

TOTALS:

FAIL RATE (Fits): 14 DEVICE HRS: 6.60E+07 0

# RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um,Neg ZTC P1R,PdpID,Low Vts,BPSG ILO, N+ESDII,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21S07	C1-	FEB '02	28808	0112	Carsem	DM048483AC	TSSOP	336	77	0
DS21S07	C1-	FEB '02	28808	0112	Carsem	DM048483AC	TSSOP	1000	77	0

TOTALS: FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0